

# 2001 - 2004 R&D on CMOS sensors for Charged Particle Tracking at a Future Linear Collider Vertex Detector

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## Outline

- Reminder: principle of operation of CMOS sensors
- Summary of sensor prototypes fabricated since 1999
- New results on tracking performances of small sensors
- Test results of first real scale prototype
- Test results of low doping substrate sensor
- Radiation tolerance
- Next major R&D steps: Sensor & System Developments
- Summary

## Advantages of Monolithic Active Pixel Sensors:

### ★ MAPS combine advantages of CCDs and of Hybrid Pixels:

♡ they provide as good spatial resolution as CCDs & can be thinned down to the same level

♡ they are much more resistant to neutron radiation and are potentially much faster than CCDs

## Principle of Operation:

★ p-type low-resistivity Si

◇ signal generated in epitaxial layer (low doping)  $\rightarrow Q_{mip} \sim 80 \text{ e}^- \text{-h pairs} / \mu\text{m}$

◇ signal charge collected by n-well

◇ excess carriers diffuse thermally to n-wells with help of reflection on boundaries with p-well and substrate (high doping)

◇ no external depletion voltage

$\Rightarrow$  watch feature size, epitaxial layer thickness, nb of metal layers, yield, ...

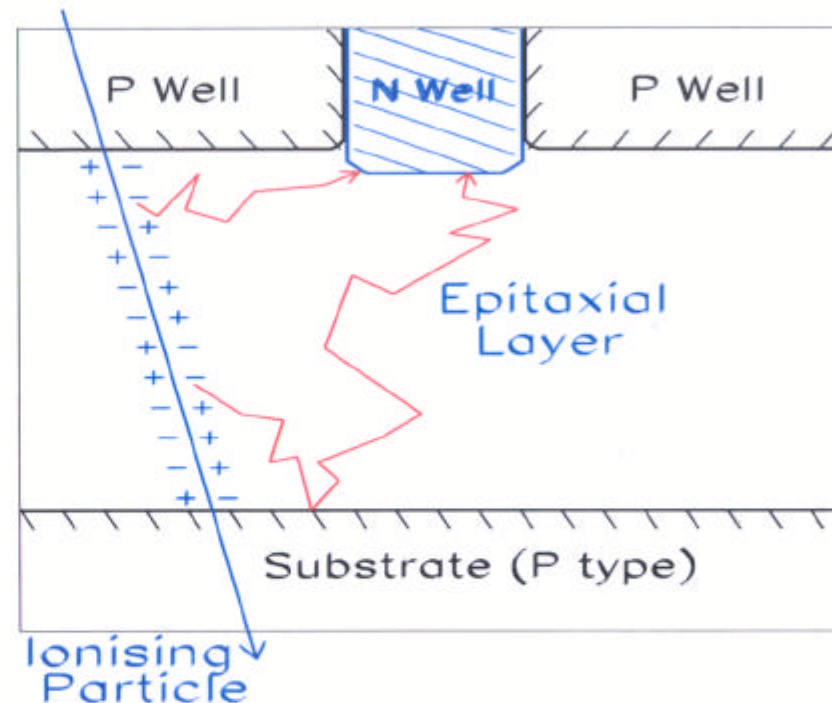


Figure 1: Schematic view of the charge collection in a CMOS sensor pixel designed for charged particle tracking.



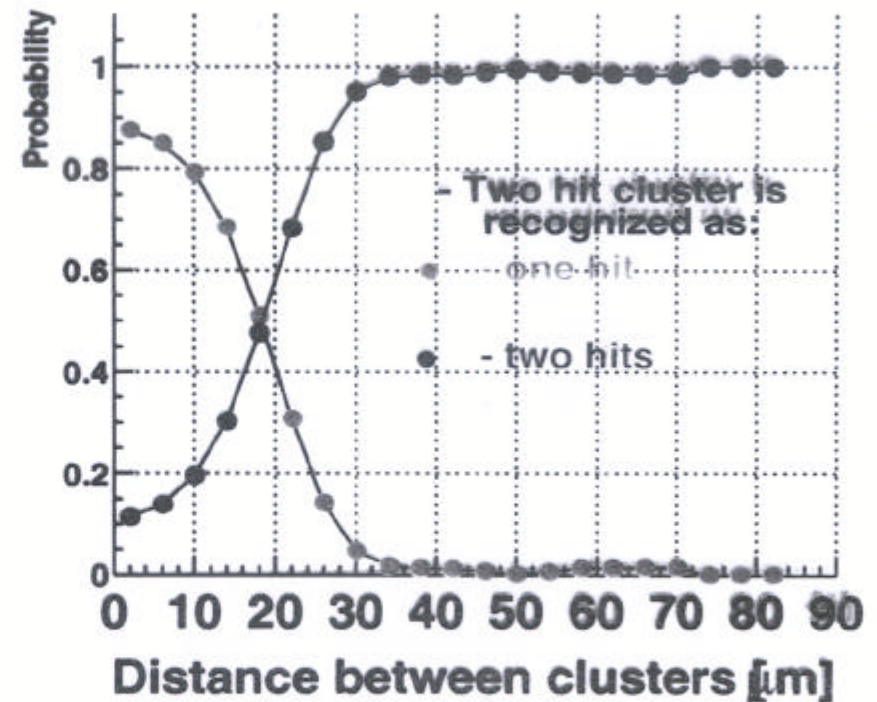
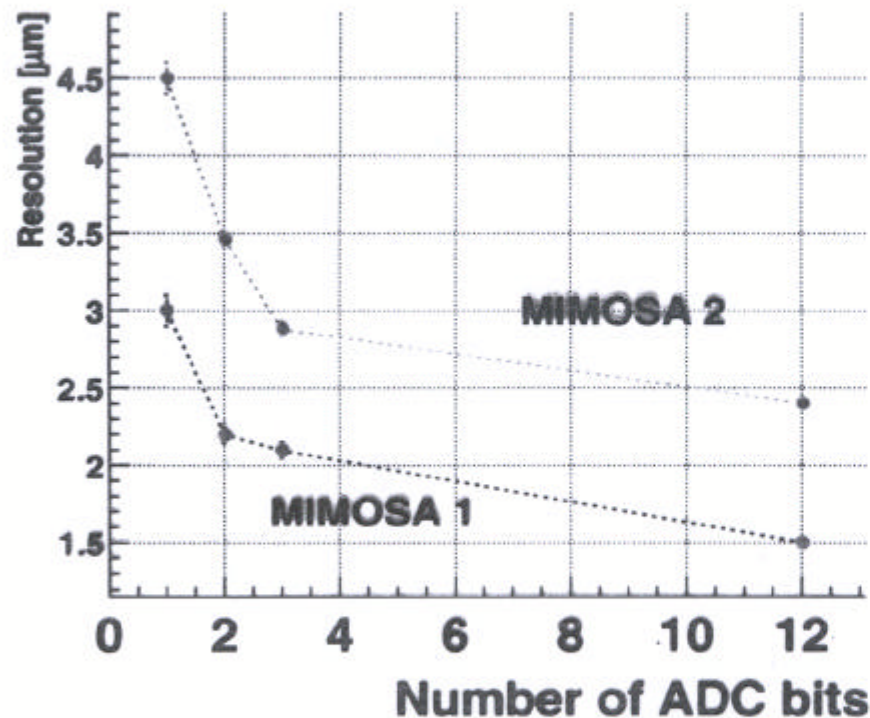
## Summary of prototypes fabricated

► 6 prototypes fabricated since 1999 (5 tested with 120 GeV/c  $\pi^-$  CERN-SPS)

sensor generation	year	process	epitax.	pitch	metal	peculiarity
MIMOSA-1	1999	AMS 0.6 $\mu m$	14 $\mu m$	20 $\mu m$	3M	thick epitaxy
MIMOSA-2	2000	MIETEC 0.35 $\mu m$	4.2 $\mu m$	20 $\mu m$	5M	thin epitaxy
MIMOSA-3	2001	IBM 0.25 $\mu m$	2 $\mu m$	8 $\mu m$	3M	deep sub- $\mu m$
MIMOSA-4	2001	AMS 0.35 $\mu m$	0 !	20 $\mu m$	3M	low doping substrate
MIMOSA-5	2001	AMS 0.6 $\mu m$	14 $\mu m$	17 $\mu m$	3M	real scale (10 <sup>6</sup> pixels)
MIMOSA-6	2002	MIETEC 0.35 $\mu m$	4.2 $\mu m$	28 $\mu m$	5M	column // r.o. integ. sparsif.

# Spatial resolution

►  $\sigma_{sp} \sim 1.5$  (2.2)  $\mu m$  with 14 (4)  $\mu m$  epitaxial layer



► single point resolution as a function of ADC-bit encoding:

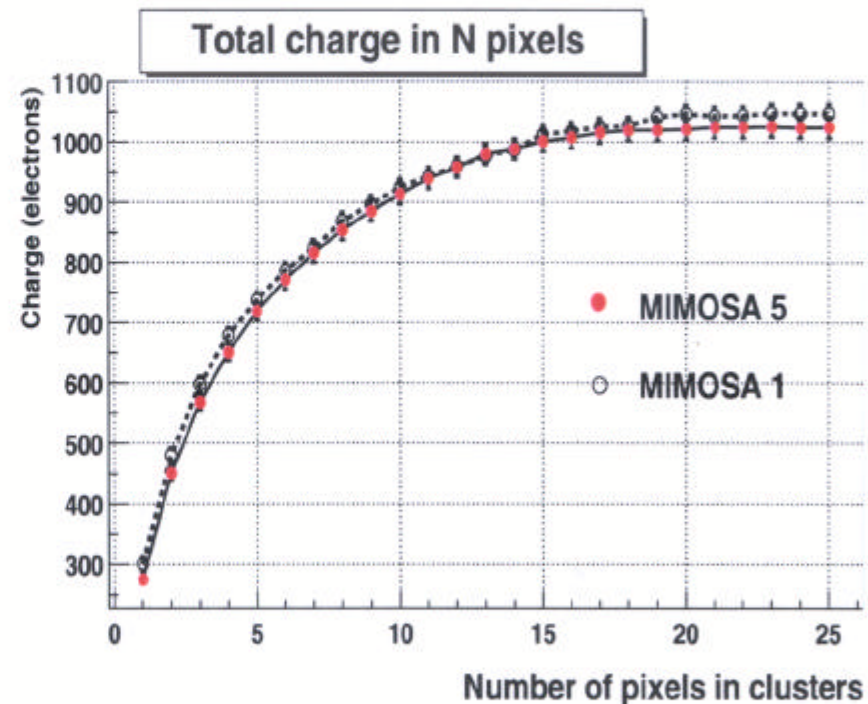
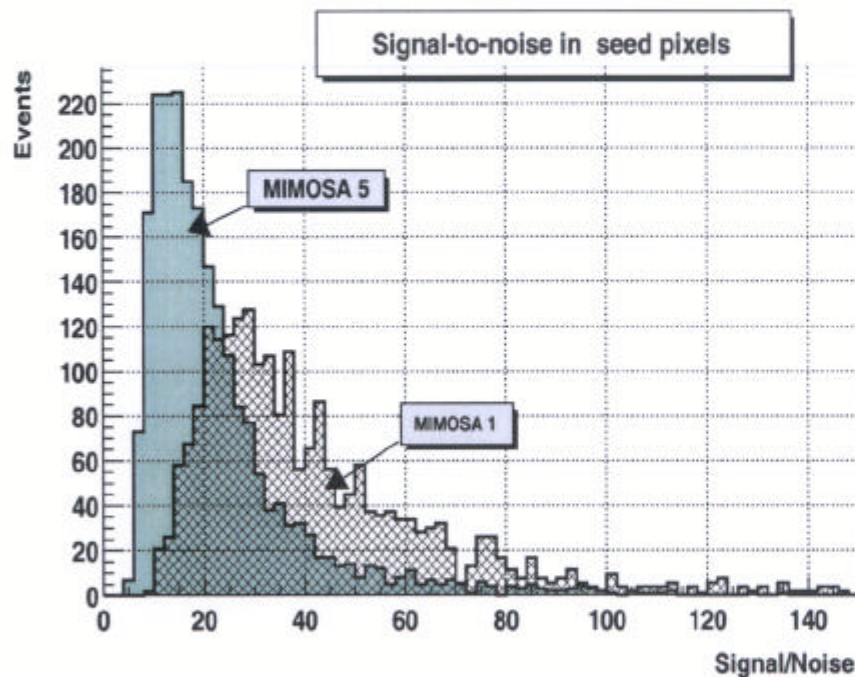
$$\sigma_{sp} \sim 2\text{-}2.5 \mu m \text{ for 3 bits } (\sim 3\text{-}4 \mu m \text{ for 1 bit } \dots)$$

► double track resolution: excellent down to 30  $\mu m$  distance  
(hit)

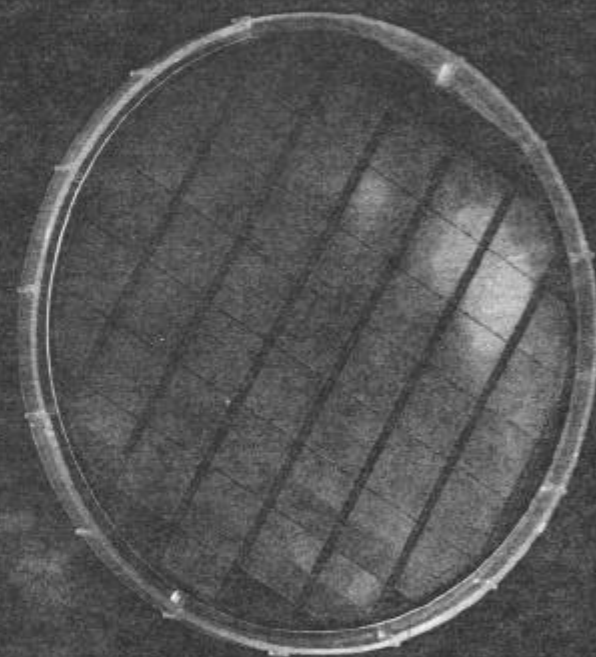
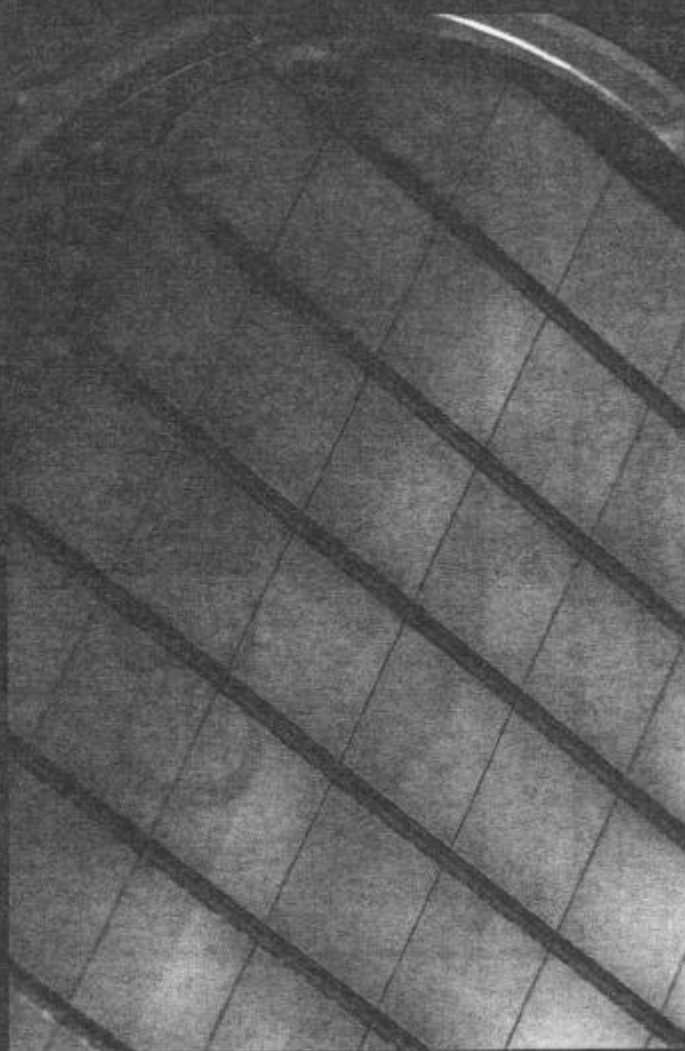
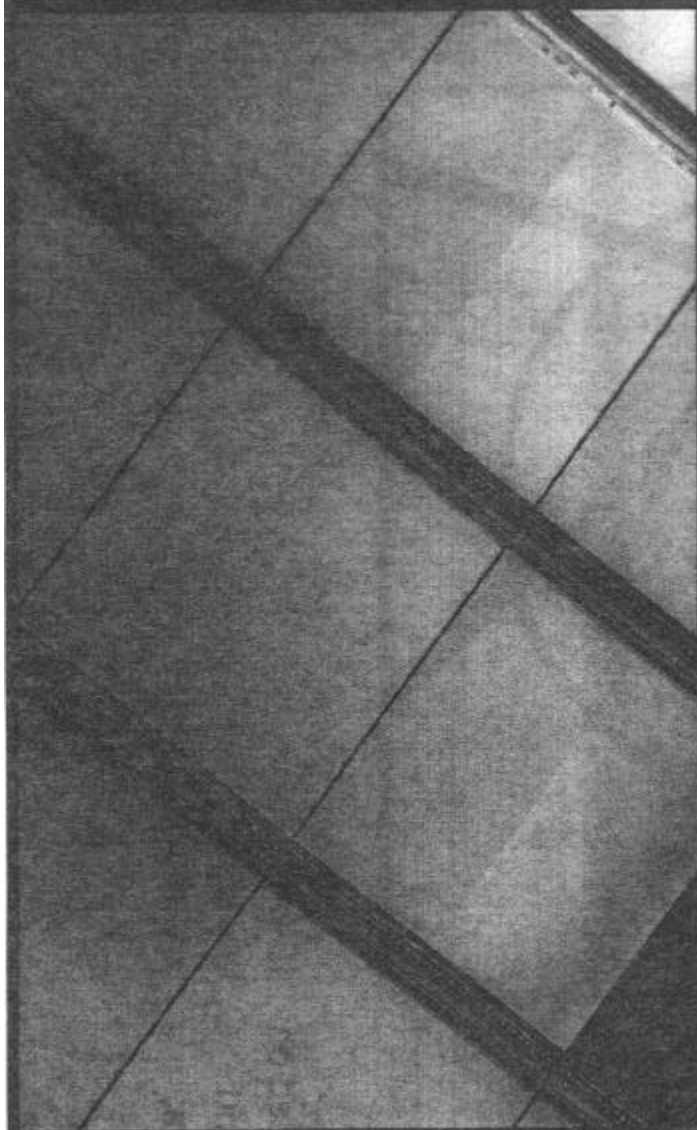


## MIMOSA-5: 1st real scale prototype

- chip of 4 matrices of  $512 \times 512$  ( $17 \times 17 \mu m^2$ ) pixels read-out in parallel, etched to  $120 \mu m$   
↳ exposed to  $120 \text{ GeV}/c \pi^-$  beam at CERN-SPS
- comparison with MIMOSA-1 (same  $0.6 \mu m$  AMS process, but  $64 \times 64$  pixels)



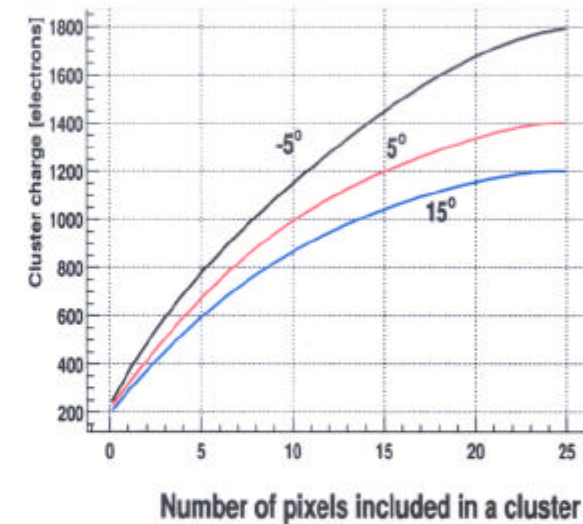
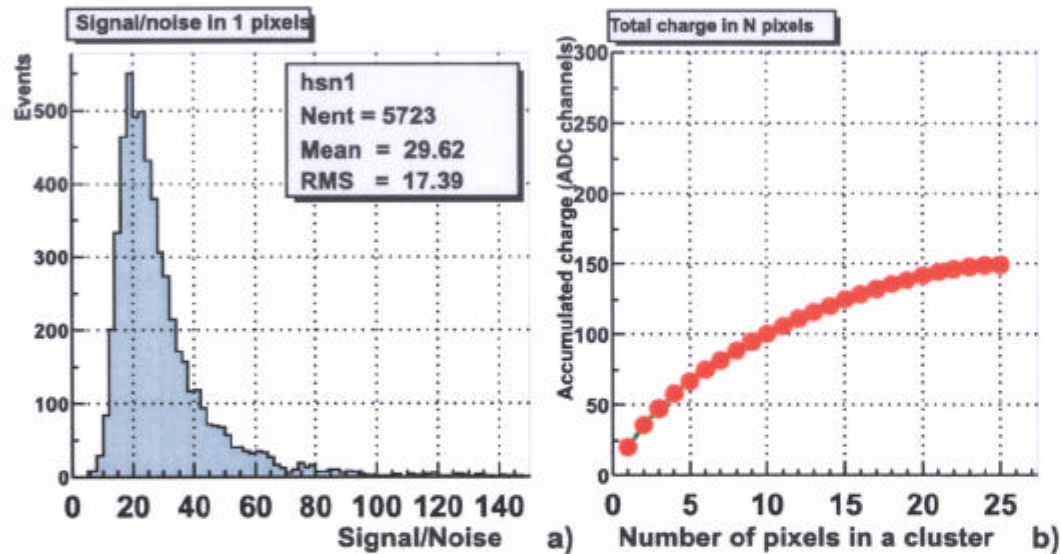
- prelim. result: detection efficiency  $\sim 99.3 \%$ ,  $\sigma_{sp} \sim 1.7 \mu m$ ,  $\sigma_{\overline{gain}} \sim 0.2 \%$   
(twice noise of M1 due to different serial r.o. architecture)





## Test results with MIMOSA-4 (1/2)

- 0.35  $\mu\text{m}$  AMS process without epitaxial layer but with low doping (resistivity) substrate

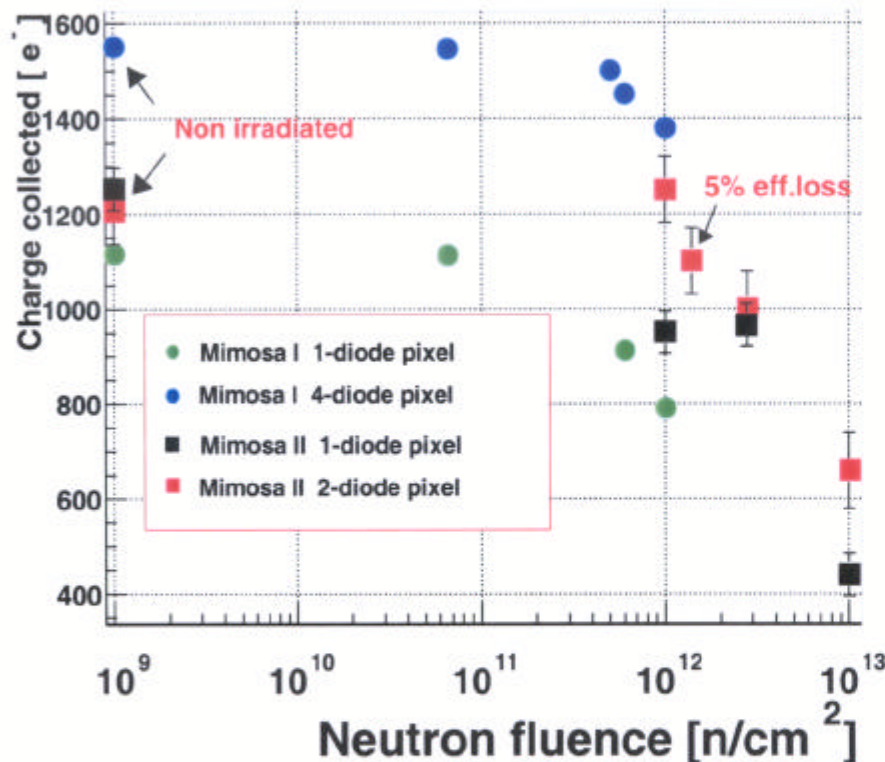


- Observed performances with 120 GeV/c  $\pi^-$  at CERN-SPS ( $T_{Room}$ ):
  - ♣ detection efficiency  $\sim 99.7\%$
  - ♣ single point resolution  $\sim 4\ \mu\text{m}$  (20  $\mu\text{m}$  pitch)
- Low temperature still improve sensor performances (studies under way)

⇒ Technology without epitaxial layer seems worth investigating & optimising



# Radiation tolerance



► Neutron irradiations up to  $10^{13} n_{eq}/cm^2$

↪ fluences of  $\lesssim 10^{12} n_{eq}/cm^2$   
are still acceptable (T effect ?)

► Ionising radiation: few 100 kRad acceptable (better if  $T \ll 0^\circ C$  ?)

↪ exact source(s) of performance loss under investigation

► Ccl: radiation tolerance at a FLC should not be an issue

(yearly:  $\sim 10^9 n_{eq}/cm^2$  and 50 kRad) X Safety Factor of 10 & 5 ?

## Plans for 2003 – 2004

### ► Sensor development towards fast signal processing & data compression:

- MIMOSA-6: col. // r.o. & integ. signal proc. → tests at CERN-SPS in June
- MIMOSA-7: alternative signal collection & processing architecture (photoFET)  
    ↪ design in  $0.25\ \mu m$  AMS ( $8\ \mu m$  epitaxy) → submission in June → tests in Autumn
- MIMOSA-8/9: best out of MIMOSA-6/7 → fast medium size sensor < Summer 2004

### ► System integration studies have started:

- ◇ DAS card being designed
- ◇ detailed effect of detector material, pixel size, etc. on  $\gtrsim 500\ \text{GeV}$  physics
- ◇ GEANT-4 description of CMOS Vertex Detector started
- ◇ pulsed powering studies with MIMOSA-5 in preparation
- ◇ estimation of limit in  $\overline{P_{diss}}$  compatible with modest active cooling
- ◇ achieve  $\lesssim 50\ \mu m$  thinning on real scale chip (MIMOSA-5)  
    ⇒ preliminary ladder prototype in 2005 (?)

### ► Find optimum of granularity\*signal proc. speed\*mat. budget with physics simulations



## Signal processing

- Governed by  $N(e_{BS}^{\pm})$  in 1st Vertex Detector layer:

$$N_{\pm}^{sim}(90^{\circ}) \gtrsim 5 \text{ e}^{\pm} / \text{cm}^2 / \text{BX at } 500 \text{ GeV (R=15 mm)}$$

$$\hookrightarrow \text{occupancy} \gtrsim 3\text{-}5 \% \text{ in } 100 \mu\text{s (m}_{clust} \sim 5)$$

- Safety factors (simulation accuracy, uncertainty on B, higher  $\sqrt{s}$ , shorter  $\Delta t_{BX}$ )

$$\rightsquigarrow \text{occ.} \gtrsim 15\text{-}25 \% \text{ in } 100 \mu\text{s}$$

- Goal:  $t_{L1} \sim 25\text{-}50 \mu\text{s}$  (R&D needed)

$$t_{lect}^{L2-5} \sim 100 \longrightarrow 200 \mu\text{s (no major difficulty)}$$

- major obstacle: data flux (L1)

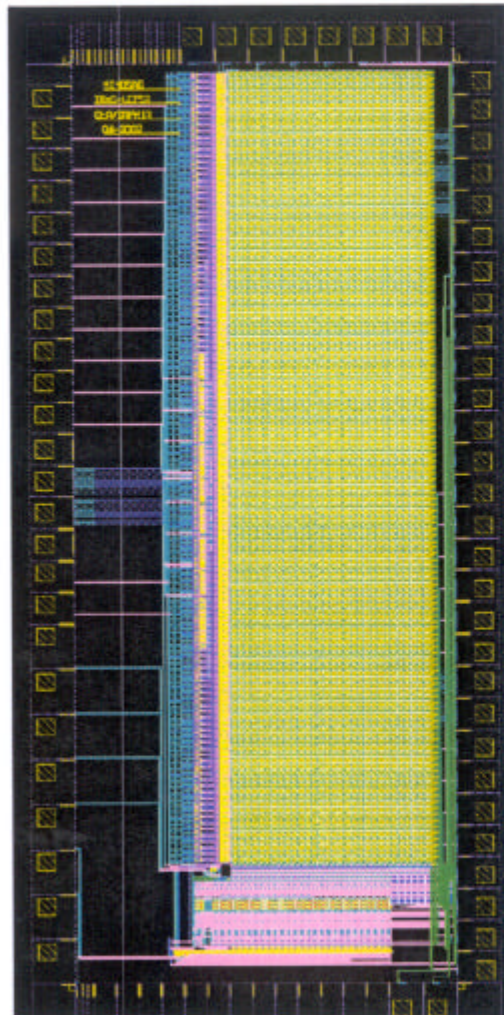
$$\hookrightarrow 15 \text{ bits/pixel, } t_{L1} \sim 25 \mu\text{s} \longrightarrow \sim 500 \text{ Gbits/s/}10^6 \text{ pixels (e}_{BS}^{\pm}: 5 \text{ Gbits/s)}$$

$\Rightarrow$  Next CMOS sensor prototypes address

**Signal Processing Speed AND Data Compression**

## MIMOSA-6: 1st sensor with col.// r.o. & integ.sparsif.

### ► 1st sensor with sparsification integrated / substrate & column // r.o.:



- amplification (x5.5) and noise suppression (CDS) on pixel
- discriminator integrated on chip periphery (1 per column)

♣ 0.35  $\mu m$  MIETEC technology (same as MIMOSA-2)

- ♣ 30 columns read-out in  $\Downarrow$  (128 pixels per column)
  - 30 MHz r.o. frequency but 6 clock cycles per pixel  
 $\Rightarrow$  5 MHz effective r.o. frequency

♣ pixels of 28  $\mu m$  pitch (29 transistors, 3 capacitors)

◁  $P_{diss} \sim 500 \mu W$  per column and frame r.o. cycle

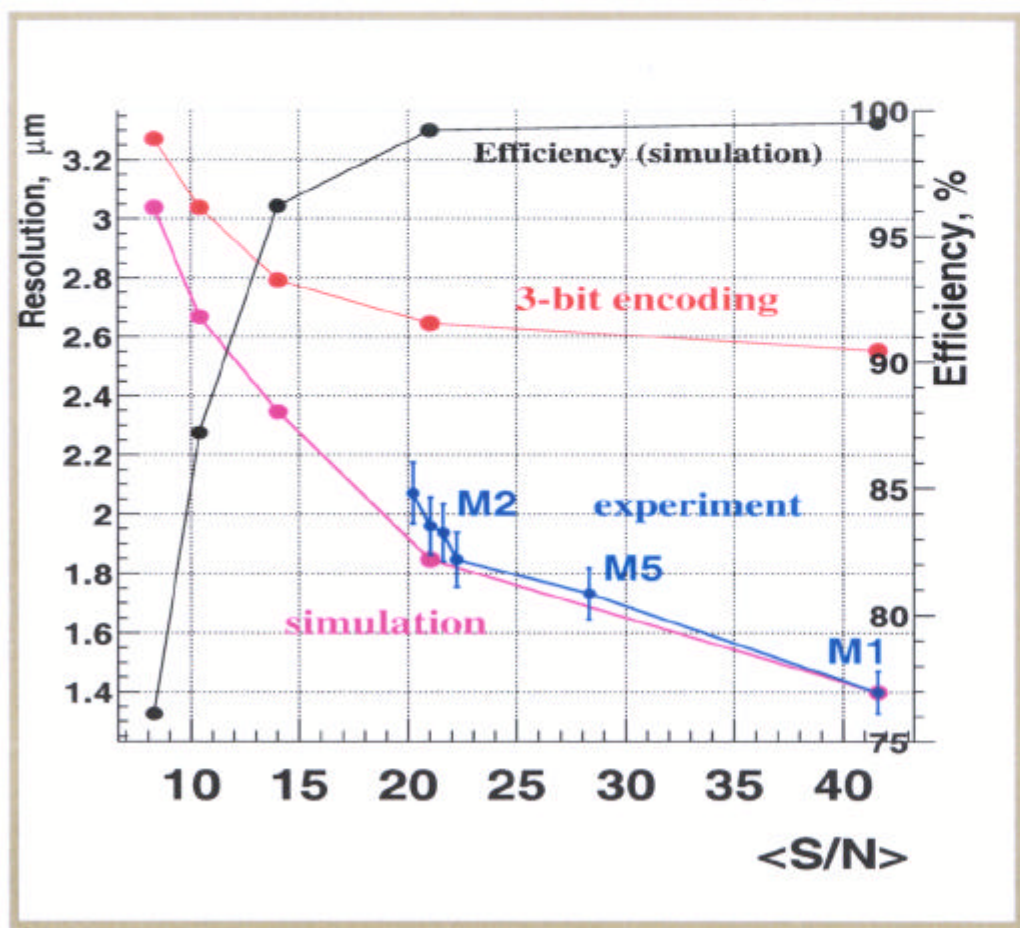
♣ tests under way in Strasbourg and Saclay



## Fast Data Processing: Effect of Increased Noise

- on-chip data proc. to reduce data flux ( $\emptyset$ ) due to fast r.o. of very granular sensors  
→ pre-amplif., noise supp., ADC, discr., ... shared between pixel and chip periphery

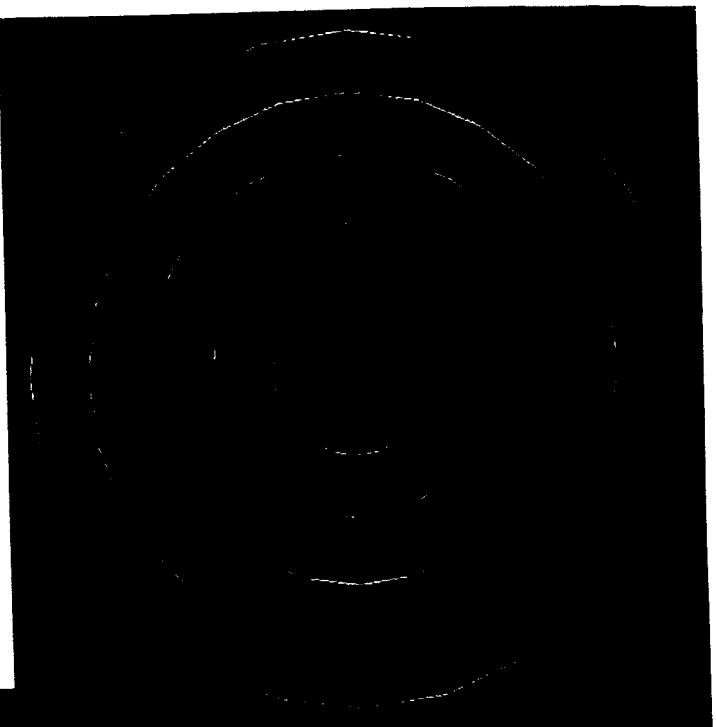
⇒ noise may increase substantially → csq on  $\epsilon_{det}$  &  $\sigma_{sp}$  ?



- Study based on M-1,-2,-5 data:

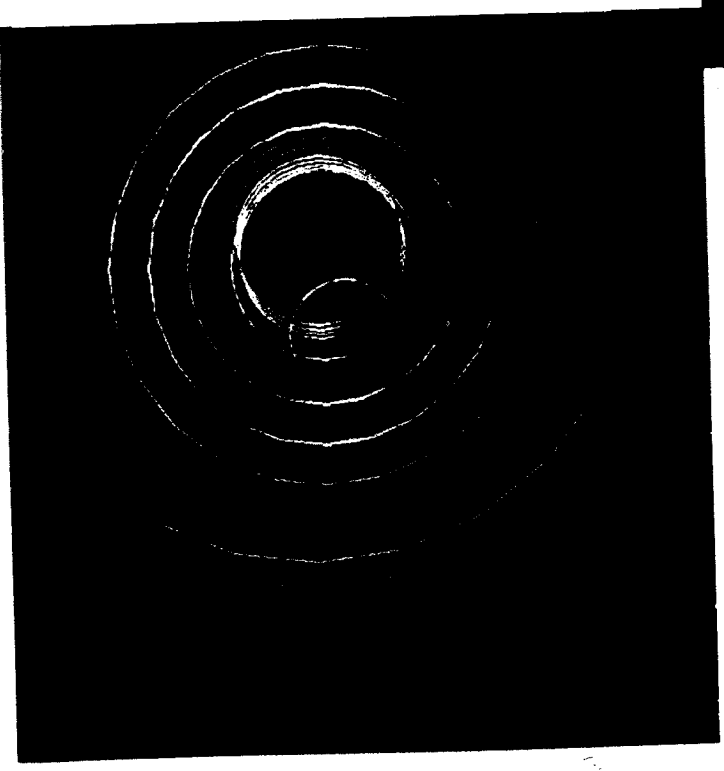
- $\epsilon_{det} \gtrsim 96\%$  if  $S/N \gtrsim 14$
- $\sigma_{sp} \lesssim 3\ \mu m$  even if  $S/N \sim 10$   
and only 3-bit encoding

## View of the VXD in MOKKA



- ➔ 50  $\mu\text{m}$  thick carbon fibre mechanical support
- ➔ 50  $\mu\text{m}$  thick CMOS sensor

$$\star X/X_0 \approx 0.08 \%$$



- Present Work :
  - ➔ tracking algorithm implementation
  - ➔ impact parameter resolution
- Caution ! This is just a starting point, the final geometry may be totally different.



## Distribution of Tasks

R&D Topic	Univ. Geneva	Univ. Hamburg	IReS-LEPSI	DESY	NIKHEF Amster.	DAPNIA
Intrinsic Perfo.			X		X	X
R.O.Circuits			X			X
Chip Tests		X	X	X		X
Rad. Tolerance		x	X	x	x	
DAS circuits	X					
Thinning			X	x	X	
Mech. & Cool.		X		X	X	

## Summary

- ◇ CMOS sensors offer a very promising technical solution for a vertex detector of unprecedented performances at a future Linear Collider
- ◇ Several requirements for this application are already fulfilled: detection efficiency, spatial resolution (3-bits), double hit resolution, radiation tolerance ( $\sim$ ), real scale sensors, low doping substrate technology, etc.
- ◇ Until 2004, substantial progress expected on fast signal processing (goal  $\sim 25 \mu s$ ) and system integration  $\rightarrow$  prototype ladder in 2005 (?)